

N-channel 60 V, 0.019 Ω typ., 8 A STripFETTM F7 Power MOSFET in a PowerFLATTM 3.3x3.3 package

Datasheet - production data

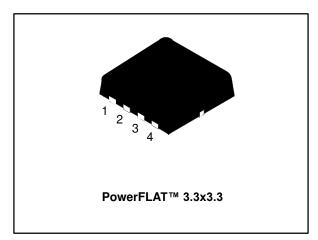
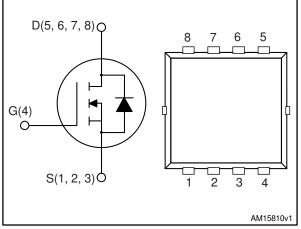


Figure 1: Internal schematic diagram



Features

Order code	V _{DS}	R _{DS(on)} max	ΙD
STL8N6F7	60 V	0.023 Ω	8 A

- Among the lowest R_{DS(on)} on the market
- Excellent figure of merit (FoM)
- Low C_{rss}/C_{iss} ratio for EMI immunity
- High avalanche ruggedness

Applications

• Switching applications

Description

This N-channel Power MOSFET utilizes STripFET™ F7 technology with an enhanced trench gate structure that results in very low onstate resistance, while also reducing internal capacitance and gate charge for faster and more efficient switching.

Table 1: Device summary

Order code	Marking	Package	Packing
STL8N6F7	8N6F7	PowerFLAT™ 3.3x3.3	Tape and reel

Contents STL8N6F7

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STL8N6F7 Electrical ratings

1 Electrical ratings

Table 2: Absolute maximum ratings

Symbol	Parameter	Value	Unit
V _{DS}	Drain-source voltage	60	V
V_{GS}	Gate-source voltage	± 20	V
I _D ⁽¹⁾	Drain current (continuous) at T _C = 25 °C	36	Α
I _D ⁽¹⁾	Drain current (continuous) at T _C = 100 °C	22	Α
I _{DM} ⁽¹⁾⁽²⁾	Drain current (pulsed)	144	Α
I _D ⁽³⁾	Drain current (continuous) at T _{pcb} = 25 °C	8	Α
I _D (3)	Drain current (continuous) at T _{pcb} = 100 °C	5	Α
I _{DM} ⁽²⁾⁽³⁾	Drain current (pulsed)	32	Α
P _{TOT} ⁽¹⁾	Total dissipation at T _C = 25 °C	60	W
P _{TOT} (3)	Total dissipation at T _{pcb} = 25 °C	3	W
T_{stg}	T _{stg} Storage temperature		°C
T_{j}	Operating junction temperature	-55 to 150	C

Notes:

Table 3: Thermal data

Symbol	Parameter		Unit
R _{thj-pcb} ⁽¹⁾	Thermal resistance junction-pcb max.	42.8	°C/W
R _{thj-case}	R _{thj-case} Thermal resistance junction-case max.		°C/W

Notes

 $^{(1)}$ When mounted on FR-4 board of 1 inch², 2oz Cu, t < 10 sec.

 $^{^{(1)}\}text{This}$ value is rated according to $R_{\text{thj-c}}.$

⁽²⁾Pulse width limited by safe operating area.

 $^{^{(3)}\}text{This}$ value is rated according to $R_{\text{thj-pcb}}.$

Electrical characteristics STL8N6F7

2 Electrical characteristics

(T_C = 25 °C unless otherwise specified)

Table 4: On /off states

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
$V_{(BR)DSS}$	Drain-source breakdown voltage	$I_D = 1 \text{ mA}, V_{GS} = 0 \text{ V}$	60			V
I _{DSS}	Zero gate voltage drain current	$V_{GS} = 0 V$ $V_{DS} = 60 V$			1	μΑ
Igss	Gate-body leakage current	V _{GS} = 20 V, V _{DS} = 0 V			100	nA
$V_{\text{GS(th)}}$	Gate threshold voltage	$V_{DS} = V_{GS}$, $I_D = 250 \mu A$	2		4	V
R _{DS(on)}	Static drain-source on-resistance	V _{GS} = 10 V, I _D = 4 A		0.019	0.023	Ω

Table 5: Dynamic

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
Ciss	Input capacitance		1	420	1	pF
Coss	Output capacitance	$V_{DS} = 30 \text{ V, } f = 1 \text{ MHz,}$	1	215	1	pF
C _{rss}	Reverse transfer capacitance	$V_{GS} = 0 V$	1	16	1	pF
Qg	Total gate charge	$V_{DD} = 30 \text{ V}, I_D = 8 \text{ A},$	1	8	1	nC
Qgs	Gate-source charge	V _{GS} = 10 V (see Figure 14: "Test circuit for gate charge	-	2.3	-	nC
Q _{gd}	Gate-drain charge	behavior")	1	2.1	1	nC

Table 6: Switching times

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
t _{d(on)}	Turn-on delay time	$V_{DD}=30~V,~I_D=4~A,~R_G=4.7~\Omega,~V_{GS}=10~V~(see~Figure~13:~"Test~circuit~for~resistive~load~switching~times")$	1	7.85	1	ns
tr	Rise time		-	3.25	-	ns
t _{d(off)}	Turn-off delay time		-	12.1	-	ns
tf	Fall time		1	3.95	1	ns

Table 7: Source-drain diode

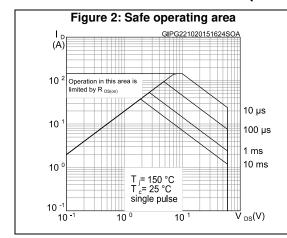
Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V _{SD} ⁽¹⁾	Forward on voltage	I _{SD} = 8 A, V _{GS} = 0 V	ı		1.2	V
trr	Reverse recovery time	$I_D = 8 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s}$	1	17.1		ns
Q_{rr}	Reverse recovery charge	V _{DD} = 48 V (see <i>Figure 15</i> :	-	6.67		nC
IRRM	Reverse recovery current	"Test circuit for inductive load switching and diode recovery times"	1	0.8		Α

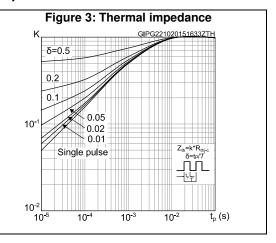
Notes:

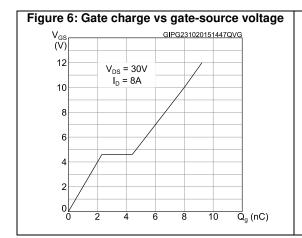
 $^{(1)}$ Pulsed: pulse duration = 300 μ s, duty cycle 1.5%

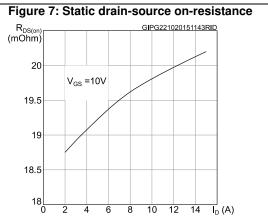


2.1 Electrical characteristics (curves)









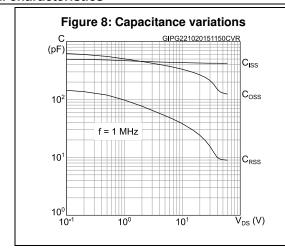
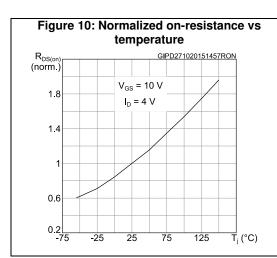
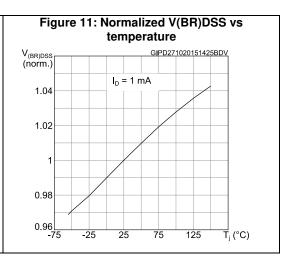
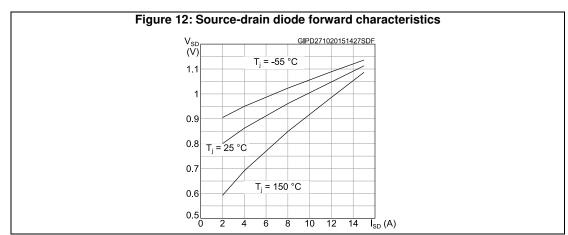


Figure 9: Normalized gate threshold voltage vs temperature V_{GS(th)} (norm.) 1.15 GIPD271020151425VTH I_D = 250 μA 1.1 1.05 0.95 0.9 0.85 0.8 0.75 0.7 -75 25 75 125 T_i (°C)







DocID028258 Rev 2

STL8N6F7 Test circuits

3 Test circuits

Figure 13: Test circuit for resistive load switching times

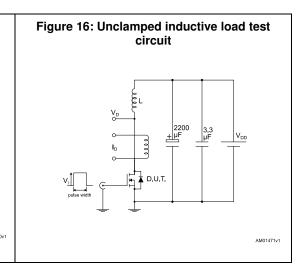
Figure 14: Test circuit for gate charge behavior

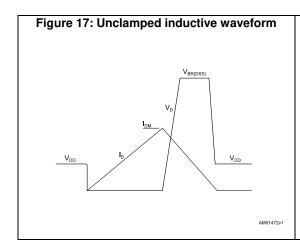
12 V 47 KΩ 100 NF D.U.T.

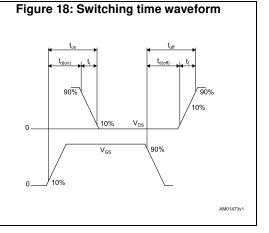
Vos 1 1 KΩ 100 NF D.U.T.

AM01488v1

Figure 15: Test circuit for inductive load switching and diode recovery times







Package information STL8N6F7

4 Package information

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In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: **www.st.com**. ECOPACK® is an ST trademark.

STL8N6F7 Package information

4.1 PowerFLAT 3.3x3.3 package information

Figure 19: PowerFLAT™ 3.3x3.3 package outline

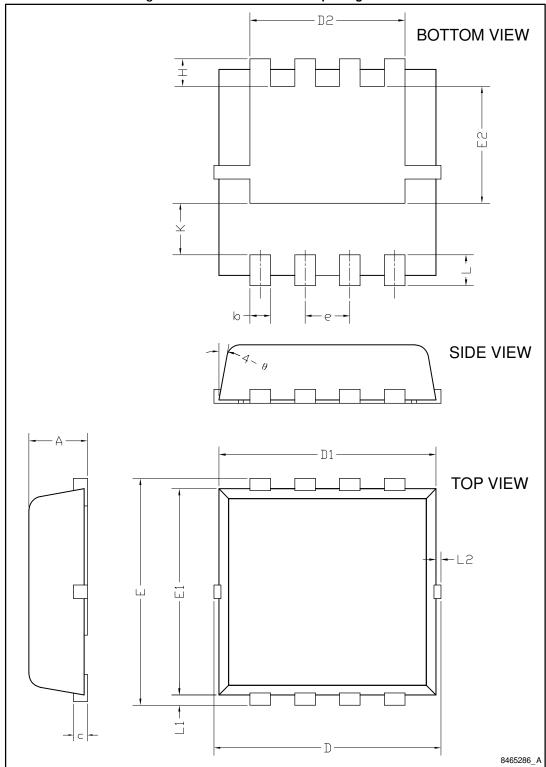


Table 8: PowerFLAT™ 3.3x3.3 package mechanical data

Dim.	mm				
Dilli.	Min.	Тур.	Max.		
Α	0.70	0.80	0.90		
b	0.25	0.30	0.39		
С	0.14	0.15	0.20		
D	3.10	3.30	3.50		
D1	3.05	3.15	3.25		
D2	2.15	2.25	2.35		
е	0.55	0.65	0.75		
E	3.10	3.30	3.50		
E1	2.90	3.00	3.10		
E2	1.60	1.70	1.80		
Н	0.25	0.40	0.55		
K	0.65	0.75	0.85		
L	030	0.45	0.60		
L1	0.05	0.15	0.25		
L2			0.15		
θ	8°	10°	12°		

0.53 2.45 (x2) = = = 0.25 MIN 0.40 MAX 8465286, footprint

Figure 20: PowerFLAT™ 3.3x3.3 recommended footprint

Revision history STL8N6F7

5 Revision history

Table 9: Document revision history

Date	Revision	Changes
20-Aug-2015	1	First release.
22-Oct-2015	2	Updated title and features in cover page. Updated Table 4: "On /off states", Table 5: "Dynamic", Table 6: "Switching times" and Table 7: "Source-drain diode". Added Section 3.1: "Electrical characteristics (curves)". Document status promoted from preliminary di production data.

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